

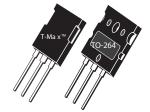


## APT22F120B2 APT22F120L

1200V, 23A, 0.70Ω Max, t<sub>rr</sub> ≤270ns

# N-Channel FREDFET

Power MOS  $8^{\text{TM}}$  is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced  $t_{rr}$ , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of  $C_{rss}/C_{iss}$  result in excellent niose immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



APT22F120B2 APT22F120L

Single die FREDFET



## **FEATURES**

- · Fast switching with low EMI
- · Low trr for high reliability
- · Ultra low Crss for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

## **TYPICAL APPLICATIONS**

- · ZVS phase shifted and other full full bridge
- · Half bridge
- PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

## **Absolute Maximum Ratings**

Symbol	Parameter	Ratings	Unit
l <sub>a</sub>	Continuous Drain Current @ T <sub>C</sub> = 25°C	23	
'D	Continuous Drain Current @ T <sub>C</sub> = 100°C	15	A
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	90	
V <sub>GS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>2</sup>	1875	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	12	Α

### **Thermal and Mechanical Characteristics**

Symbol	Characteristic	Min	Тур	Max	Unit	
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25°C			1040	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.12	0.12 °C/W	
R <sub>ecs</sub>	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature Range	-55		150	150 °C	
T <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W <sub>T</sub>	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Torque (TO 204 Pookers) A 40 or M2 corqui			10	in∙lbf	
	Mounting Torque (TO-264 Package), 4-40 or M3 screw			1.1	N·m	

Symbol	Parameter	Test Conditi	ons	Min	Тур	Max	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 2$	250μΑ	1200			V
$\Delta V_{BR(DSS)}/\Delta T_{s}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I	<sub>O</sub> = 250µA		1.41		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance <sup>®</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> =	= 12A		0.53	0.70	Ω
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	\/ -\/   -	2.5m/\	2.5	4	5	٧
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_{D} =$	2.5IIIA		-10		mV/°C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 1200V T <sub>J</sub> = 25°C				250	μA
'DSS	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_{J} =$	= 125°C			1000	μΑ
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±30\	/			±100	nA

## **Dynamic Characteristics**

## T<sub>1</sub> = 25°C unless otherwise specified

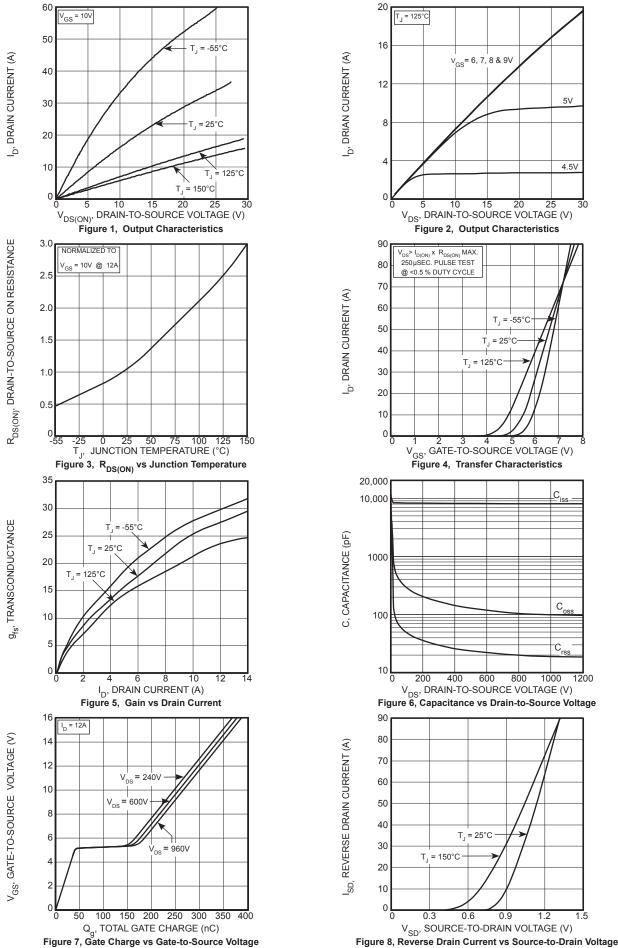
Dynamic C	ilaracteristics I J = 20	20 0 uniess otherwise specified					
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
9 <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> = 50V, I <sub>D</sub> = 12A		27		S	
C <sub>iss</sub>	Input Capacitance	V 0V V 05V		8370			
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		100			
C <sub>oss</sub>	Output Capacitance	1 111112		615			
C <sub>o(cr)</sub> ④	Effective Output Capacitance, Charge Related	V = 0V V = 0V to 900V		240		pF	
C <sub>o(er)</sub> ⑤	Effective Output Capacitance, Energy Related	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 800V		125			
$Q_g$	Total Gate Charge	V = 0 to 40V   = 40A		260			
$Q_{gs}$	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 12A,$ $V_{DS} = 600V$		42		nC	
Q <sub>gd</sub>	Gate-Drain Charge	V <sub>DS</sub> = 800V		120			
t <sub>d(on)</sub>	Turn-On Delay Time	Resistive Switching		45			
t <sub>r</sub>	Current Rise Time	V <sub>DD</sub> = 800V, I <sub>D</sub> = 12A		27		ne	
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G} = 2.2\Omega^{\textcircled{6}}, V_{GG} = 15V$		145		ns	
t <sub>f</sub>	Current Fall Time			42			

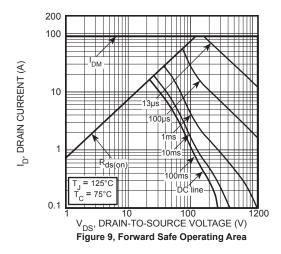
#### Source-Drain Diode Characteristics

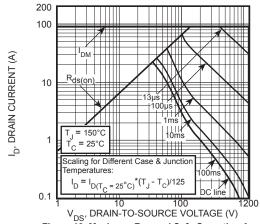
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I <sub>s</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the showing the			23	A
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>①</sup>	integral reverse p-n junction diode (body diode)	6		90	A
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 12A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> = 25°C		375	425	ns
,u.		T <sub>J</sub> = 125°C		720	850	115
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{SD} = 12A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		2.2		IIC.
rr		$di_{SD}/dt = 100A/\mu s$ $T_{J} = 125^{\circ}C$		5.8		μC
	Reverse Recovery Current	T <sub>J</sub> = 25°C		12.3		Α
'rrm		T <sub>J</sub> = 125°C		16.5		^
dv/dt	Peak Recovery dv/dt	I <sub>SD</sub> ≤ 12A, di/dt ≤1000A/μs, V <sub>DD</sub> = 800V, T <sub>J</sub> = 125°C			25	V/ns

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at  $T_J = 25$ °C, L = 26.04mH,  $R_G = 25\Omega$ ,  $I_{AS} = 12A$ .
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- C<sub>o(cr)</sub> is defined as a fixed capacitance with the same stored charge as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>.
   C<sub>o(er)</sub> is defined as a fixed capacitance with the same stored energy as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>. To calculate C<sub>o(cr)</sub> for any value of V<sub>DS</sub> less than V<sub>(BR)DSS</sub>, use this equation: C<sub>o(er)</sub> = -3.80E-7/V<sub>DS</sub><sup>2</sup> + 4.62E-8/V<sub>DS</sub> + 6.57E-11.
- $\bigcirc$  R<sub>G</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.









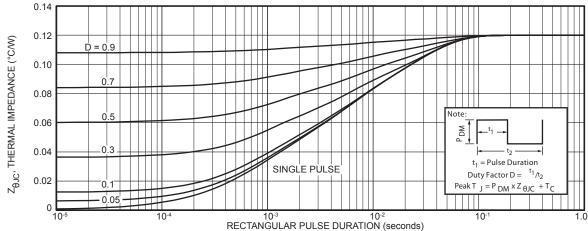


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

#### T-MAX® (B2) Package Outline TO-264 (L) Package Outline e3 100% Sn Plated 4.60 (.181) 5.21 (.205) 1.80 (.071) 2.01 (.079) 15.49 (.610) 16.26 (.640) 5.38 (.212) 6.20 (.244) Drai n 20.80 (.819) 21.46 (.845) 4.50 (.177) Max. 1.65 (.065) 2.13 (.084) 19.81 (.780) 20.32 (.800) 19.81 (.780) 21.39 (.842) Gate Drai n Drain Source 0.76 (.030) 1.30 (.051) 2.79 (.110) 3.18 (.125) 2.21 (.087) 2.59 (.102) 5.45 (.215) BSC 5.45 (.215) BSC These dimensions are equal to the TO-247 without the mounting hole. 2-Plcs. Dimensions in Millimeters and (Inches) Dimensions in Millimeters and (Inches)

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25.163.2453	0 25.163.4253.0	25.190.2053.0	25.194.3453.0	25.320.4853.1	25.320.5253.1	25.326.3253.1	25.326.3553.1	25.330.1653.1
25.330.4753	1 25.330.5253.1	25.334.3253.1	25.334.3353.1	25.350.2053.0	25.352.4753.1	25.522.3253.0	<u>T483C</u> <u>T484C</u>	<u>T485F</u> <u>T485H</u>
T512F-YEB	<u>T513F</u> <u>T514F</u>	T554 T612FSE	25.161.3453.0	25.179.2253.0	25.194.3253.0	25.325.1253.1	25.326.4253.1	25.330.0953.1
25.332.4353.	25.350.1653.0	25.350.2453.0	25.352.1453.0	25.352.1653.0	25.352.2453.0	25.352.5453.1	25.522.3353.0	25.602.4053.0
25.640.5053.	0							